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Zhengji Xu**
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Contents

vii *Conference Committee*

OPTICAL IMAGING SYSTEMS AND APPLICATIONS

- 13736 02 **Characterization of polished silicon wafer surfaces and its light scattering analysis using the FDTD method** [13736-5]
- 13736 03 **Optical orbital angular momentum single-pixel imaging technology** [13736-41]
- 13736 04 **Imaging system for mid-wave infrared cooled detectors** [13736-8]
- 13736 05 **Self-calibrated surface plasmon resonance imaging detection method using wavelength interrogation** [13736-16]
- 13736 06 **Design and comparison of lightweight and compact imaging spectrometer based on unmanned aerial vehicle** [13736-28]
- 13736 07 **Full-field personalized spectacle design and validation for correcting high-order aberrations of the human eye** [13736-19]
- 13736 08 **Design and research of microprojection system based on Micro-LED** [13736-38]
- 13736 09 **Analysis of the influence of dispersive objective lenses on spectral confocal interferometry systems** [13736-35]
- 13736 0A **Optical design of laser scanning interferometer confocal microscope system** [13736-15]
- 13736 0B **Curvature weighted total variation minimization for limited angle CT reconstruction** [13736-11]
- 13736 0C **Detection of microbubble defects for bonding components using optical coherence tomography** [13736-23]
- 13736 0D **Design and implementation of the reliability algorithm for the metrology process of instruments and meters** [13736-37]
- 13736 0E **Ultrasonic levitation droplet simulation device for multidisciplinary applications** [13736-43]
- 13736 0F **Modification of graphite particle mass concentration measurement method based on mass equivalent and optical equivalent** [13736-4]
- 13736 0G **Research on simulation and localization methods of ultrasonic guided wave damage in composite material box-type laminates** [13736-42]

- 13736 OH **Determination of color and precious metal content of gold rimming silver jewelry** [13736-36]
- 13736 OI **Circular shears defect detection based on time-frequency analysis and convolutional neural network** [13736-26]

DETECTION AND MEASUREMENT TECHNOLOGIES

- 13736 OJ **Intelligent recognition and vectorization automatic extraction technology of mining area buildings based on high-resolution remote sensing images** [13736-3]
- 13736 OK **Fabrication and properties of Ga₂O₃ films on flexible PET substrates** [13736-32]
- 13736 OL **Accurate measurement of CH₄ based on direct absorption spectroscopy** [13736-10]
- 13736 OM **Research on data augmentation method of ion mobility spectrometry and its application in classification of the simulants of chemical warfare agents** [13736-21]
- 13736 ON **In-service inspection equipment and technology development for butt welds of CRDM pipe seats and through fittings** [13736-46]
- 13736 OO **Carbon nanotube-based field-effect transistor for highly sensitive detection of foodborne pathogens** [13736-18]
- 13736 OP **Topography detection method of microlens array based on improved TIE** [13736-40]
- 13736 OQ **Research on welding defect detection technology** [13736-6]
- 13736 OR **Application of active-passive source collaborative seismic frequency-domain imaging technology in marine riprap foundation detection** [13736-17]
- 13736 OS **Obstacle identification and classification method utilizing laser displacement sensors** [13736-20]
- 13736 OT **Simulation and experimental research on metal loss detection in the interior of pipelines based on array eddy current detection method** [13736-22]
- 13736 OU **Identifying optimal relative humidity and engineering strategies for phase-transition-based aerosol samplers in airborne virus surveillance** [13736-7]
- 13736 OV **Research of an in situ dust measuring instrument for real-time dust monitoring** [13736-2]
- 13736 OW **A wide-range suspended sediment concentration monitoring method** [13736-31]
- 13736 OX **Research on deformation monitoring of Guanyin Temple Dam based on industrial photogrammetry** [13736-30]

- 13736 0Y **A study on purification efficiency of water purifier based on intelligent continuous dosing method [13736-29]**
- 13736 0Z **Steel surface defect detection algorithm based on TCS-YOLOv7 [13736-14]**
- 13736 10 **Research on quality recognition of rebar binding based on YOLOv5 [13736-45]**